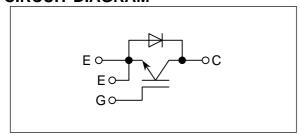
MBN400GR12A

[Rated 400A/1200V, Single-pack type]

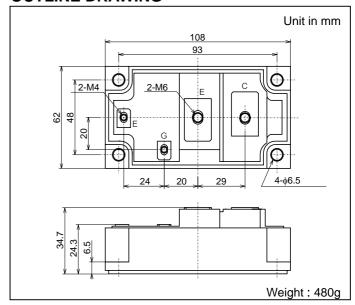
FEATURES

- Low saturation voltage and high speed.
- Low turn-OFF switching loss.
- Low noise due to built-in free-wheeling diode.
 (Ultra Soft and Fast recovery Diode (USFD))
- High reliability structure.
- Isolated heat sink (terminals to base).

CIRCUIT DIAGRAM



OUTLINE DRAWING



ABSOLUTE MAXIMUM RATINGS (T_C=25°C)

Item		Symbol	Unit	Value		
Collector-Emitter Voltage		V _{CES}	V	1200		
Gate-Emitter Voltage		V_{GES}	V	±20		
Collector Current	DC	I _C	Α	400		
	1ms	I _{CP}	A	800		
Forward Current	DC	I _F	Α	400 *1		
	1ms	I _{FM}	^	800		
Collector Power Dissipation		Pc	W	2500		
Junction Temperature		Tj	°C	-40 ~ + 150		
Storage Temperature		T _{stg}	°C	-40 ~ +125		
Isolation Voltage		V _{iso}	V_{RMS}	2500(AC 1 minute)		
Screw Torque	Terminals(M4/M6)		N∙m	1.37 / 2.94		
	Mounting	<u>—</u>		2.94 *3		

Notes; *1 : RMS current of diode ≤ 120 Arms

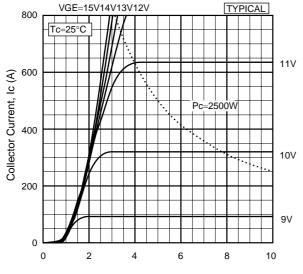
*2 : Recommended value 1.18 / 2.45 N·m

*3 : Recommended value 2.45 N·m

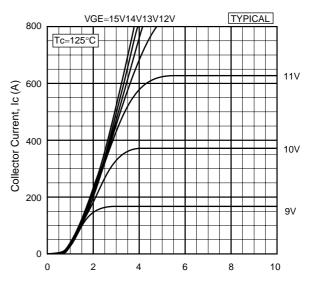
CHARACTERISTICS (T_C=25°C)

CHARACTERISTICS (TC=25 C)									
Item		Symbol	Unit	Min.	Тур.	Max.	Test Conditions		
Collector-Emitter Cut-Off Current		I _{CES}	mA	_	_	1.0	V _{CE} =1200V, V _{GE} =0V		
Gate-Emitter Leakage Current		I _{GES}	nA	_	_	±500	V _{GE} =±20V, V _{CE} =0V		
Collector-Emitter Saturation Voltage		V _{CE(sat)}	V	_	2.2	2.8	I _C =400A, V _{GE} =15V		
Gate-Emitter Threshold Voltage		V _{GE(TO)}	V	_	_	10	V _{CE} =5V, I _C =400mA		
Input Capacitance		C _{ies}	рF	_	36000	_	V _{CE} =10V, V _{GE} =0V, f=1MHz		
Switching Times	Rise Time	t _r	μS	_	0.2	0.5	V _{CC} =600V, I _C =400A		
	Turn-On Time	t _{on}		_	0.35	0.7	$R_G=2.7\Omega$ *4 $V_{GE}=\pm15V$ Inductive Load		
	Fall Time	t _f		_	0.15	0.3			
	Turn-Off Time	t _{off}		_	0.7	1.1			
Peak Forward Voltage Drop		V_{FM}	V	_	2.5	3.5	I _F =400A, V _{GE} =0V		
Reverse Recovery Time		t _{rr}	μS	_	_	0.4	I _F =400A, V _{GE} =-10V,di/dt=400A/μs		
Thermal Impedance	IGBT	R _{th(j-c)}	°C/W	_	1	0.05	Junction to case		
	FWD	R _{th(j-c)}				0.1			

Notes; *4: R_G value is the test condition's value for decision of the switching times, not recommended value, please determine the suitable R_G value after the measurement of switching waveforms (overshoot voltage, etc.) with appliance mounted. Remark; For actual application, please confirm this spec. sheet is the newest revision.

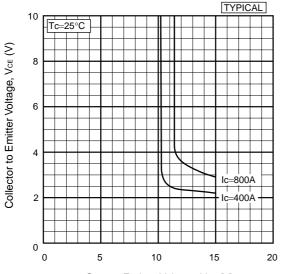


Collector to Emitter Voltage, VcE (V)
Collector current vs. Collector to Emitter voltage

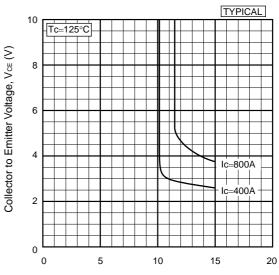


Collector to Emitter Voltage, VCE (V)

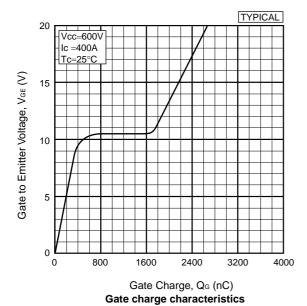
Collector current vs. Collector to Emitter voltage

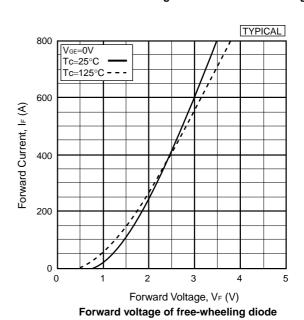


 $\label{eq:Gate to Emitter Voltage, Vge} Gate \ to \ Emitter \ voltage \ vs. \ Gate \ to \ Emitter \ voltage$

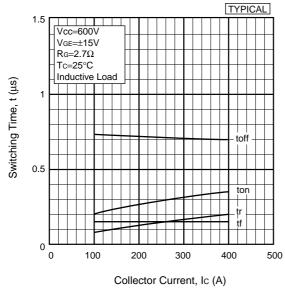


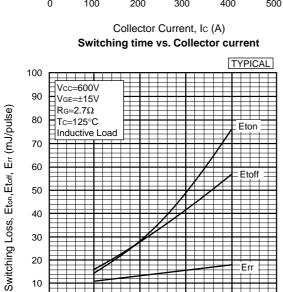
 $\label{eq:Gate to Emitter Voltage, Vge} Gate \ to \ Emitter \ voltage \ vs. \ Gate \ to \ Emitter \ voltage$





PDE-N400GR12A-0





Collector Current. Ic (A)
Switching loss vs. Collector current

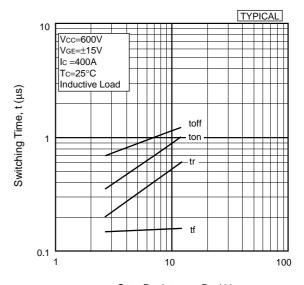
300

500

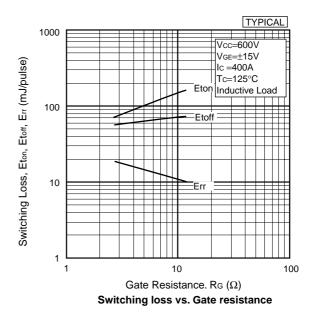
200

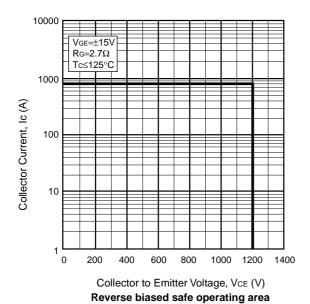
100

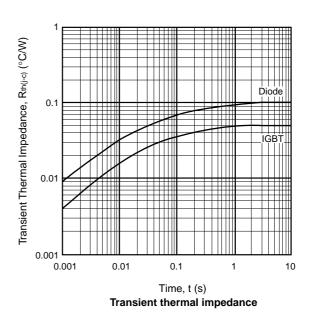
0 0



 $\label{eq:Gate Resistance} \mbox{Gate Resistance, Rg }(\Omega) \\ \mbox{Switching time vs. Gate resistance}$







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